

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components, Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 09.0012

CB Certificate No.: T1088

Schedule Number: IECQ-L ULTW 09.0012-S Rev No.: 5 Revision Date: 2016/05/28 Page 1 of 2

Schedule of Scope to Certificate of Approval

Test Items	Standard/Method
Temperature Cycling test	IEC60068-2-14
Low Temperature test	IEC60068-2-1
Salt Mist test	IEC 60068-2-11, MIL-STD-202 Method 101
Highly accelerated life test	MIL-HDBK 338
Mating & Unmated Force test	EIA-364-13
Durability test	EIA-364-09
Vibration	EIA-364-28, IEC60068-2-6, IEC60068-2-64
Shock test	MIL-STD-202 Method 213 Condition A, EIA-364-27, IEC60068-2-27
Discontinuities test	EIA-364-46
Humidity	EIA-364-31, IEC60068-2-30, IEC60068-2-38
Discharge performance/Charge recovery after long term storage tests	IEC 61960
Dry Heat	IEC60068-2-2
Insulation resistance test	MIL-STD-202F Method 302, EIA-364-21
Contact resistance	MIL-STD-1344Method 3002 /EIA-364-23/EIA-364-06
Dielectric voltage test	MIL-STD-202 Method 301, EIA-364-20
Capacitance test	MIL-STD-202 Method 305,EIA-364-30
Temperature rise test	EIA-364-70
Temperature Life test	EIA-364-17
Free Fall test	IEC60068-2-32
High temperature aging test	MIL-STD-202 Method 108

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Steam aging test	MIL-STD-202 Method 208, EIA-364-52,
	IPC/ECA J-STD-002
Solderability test	MIL-STD-202 Method 208, EIA-364-52,
	IPC/ECA J-STD-002
Thermal shock test	MIL-STD-202 Method 107, EIA-364-32
Constant temperature & humidity test	MIL-STD-202 Method 103, EIA-364-31
Mixed Flowing Gas	EIA-364-65, IEC 60068-2-60
Bump Test	IEC60068-2-29
Low air pressure Test	IEC60068-2-13
Charging procedure for test purposes	IEC 62133
Continuous low-rate charging	
Vibration	
Temperature cycling	
Incorrect installation cell	
External short circuit	
Free fall	
Mechanical shock	
Thermal abuse	
Crushing of cells	
Low pressure	
Overcharge	
Forced discharge	
Continuous charging at constant voltage	
Altitude (T1)	UN38.3
Thermal (T2)	
Vibration (T3)	
Shcok (T4)	
External short circuit (T5)	
Crush test(T6)	
Force discharge (T8)	

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